



# SLOVENSKI STANDARD

DSIST EN 301 614-3:2003

01-bcj Ya VYr-2003

8 [[ ]HUbY]nVc`yUbYvfYnj fj ] bYhY\_Y ca i b]\_UMY'fB 97 HL! '8 [[ ]HJbc`ca fYy'Y'n  
]bhY[ f]fUb]a ]'ghcf]hj Ua ]'fHG8 Bk! 'JnUYa bc`XYcj Ub'Y'8 97 H#G8 B'j `cV[]  
dcgfYXcj UbY[ Ug]ghYa U!' "XY. 'DfYg\_i yYj UbUgdYWZ]\_UMY'UzcXj ]gbUcX'dfcZ`U  
fDGHGZnUZ]\_gbc`fUX]`g\_c`nU`'f ]hYj`fi HL

Digital Enhanced Cordless Telecommunications (DECT); Integrated Services Digital Network (ISDN); DECT/ISDN interworking for intermediate system configuration; Part 3: Profile Specific Test Specification (PSTS) for Fixed radio Termination (FT)

Ta slovenski standard je istoveten z: EN 301 614-3 V1.1.2.2003

**ICS:**

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à!^: ç!çã } ^ Á ^ \ [ { ~ } ä æ å  
ÖÖÖVD      Digital Enhanced Cordless  
Telecommunications (DECT)
- 33.080      Digitalno omrežje z  
integriranimi storitvami  
(ISDN)      Integrated Services Digital  
Network (ISDN)

DSIST EN 301 614-3:2003      en



# EN 301 614-3 V1.1.2 (1999-02)

*European Standard (Telecommunications series)*

**Digital Enhanced Cordless Telecommunications (DECT);  
Integrated Services Digital Network (ISDN);  
DECT/ISDN interworking for  
intermediate system configuration;  
Part 3: Profile Specific Test Specification (PSTS) for  
Fixed radio Termination (FT)**



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**Keywords**

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